
U.S. PATENT DOCUMENTS					
Examiner	Cite	Document	Publication	Name of Patentee or Applicant Relevant F	
Initials*	No.	Number	Date	Name of Fateritee of Applicant	Cols, Lines, Figs.
	AA	US-4,028,938	06/14/77	Eck	
	AĐ	US-4,754,650	07/05/88	Smalling et al.	
	AC	US-5,123,286	06/23/92	Baumgärtner	
	AD	US-5,230,341	07/27/93	Polaschegg	
	AE	US-6,212,936 B1	04/10/01	Meisberger	
	AE	US-6,226,598 B1	05/01/01	De Vanssay et al.	
	AG	US-6,527,728 B2	03/04/03	Zhang	
	АН	US-6,542,761 B1	04/01/03	Jahn et al.	
160	Al	US-6,568,281 B1	05/27/03	Sato et al.	
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## FOREIGN PATENT DOCUMENTS

-Examiner Initials*	Cite No.	Country Code + Number	Publication Date	Name of Patentee or Applicant	Relevant Pages, Cols, Lines, Figs.	Translation
- 1211	AK	DE 34 20 794 A1	12/13/84	Heimel et al.		Abstract
	AL	EP 0 855 577 A1	07/29/98	Eusemann et al.		Abstract
	AM	EP 0 899 564 A2	03/03/99	Meisberger		Equivalent
	AR	EP 0 902 883	03/24/99	De Vanssay et al.		No
	AO	WO 97/46854	11/12/97	De Vanssay et al.		Equivalent
	AP	DE 198 09 945 A1	03/03/99	Christmann-Braun et al.		Equivalent
	ΑO	EP 0 943 369 A1	09/22/99	Christmann-Braun et al.		Abstract
	AR	EP 1 077 365 A2	02/21/01	Sato et al.		Equivalent
	AS	DE 100 51 943 A1	05/16/02	Zhang		Equivalent
	ΑT	DE 101 06 308 C1	07/11/02	Puettmer et al.		Abstract

## NON-PATENT LITERATURE DOCUMENTS

Examiner	Cite	Include name of author in CAPS; title of article; title of book, magazine, journal etc.; date; page(s); volume/issue
Initials*	No.	number(s); publisher; city and/country where published.
	ΑU	
	AV	
	AW	

/Jacques Saint Surin/ 11/08/2008 Signature Considered \*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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